

2Mx32 5V NOR FLASH MODULE



WF2M32-XXX5

FEATURES

- Access Time of 90, 120, 150ns
- Packaging:
 - 66 pin, PGA Type, 1.185" square, Hermetic Ceramic HIP (Package 401).
 - 68 lead, Hermetic CQFP (G2U), 22.4mm (0.880") square (Package 510) 3.56mm (0.140") height. Designed to fit JEDEC 68 lead 0.990" CQFJ footprint (FIGURE 3)
- Sector Architecture
 - 32 equal size sectors of 64KBytes per each 2Mx8 chip
 - Any combination of sectors can be erased. Also supports full chip erase.
- Minimum 100,000 Write/Erase Cycles Minimum
- Organized as 2Mx32
- Commercial, Industrial, and Military Temperature Ranges
- 5 Volt Read and Write

- Low Power CMOS
- Data# Polling and Toggle Bit feature for detection of program or erase cycle completion.
- Supports reading or programming data to a sector not being erased.
- RESET# pin resets internal state machine to the read mode.
- Built in Decoupling Caps and Multiple Ground Pins for Low Noise Operation, Separate Power and Ground Planes to improve noise immunity

* This product is subject to change without notice.
 Note: For programming information and waveforms refer to Flash Programming 16M5 Application Note AN0038. RESET# and RY/BY# function and timings don't apply to this device.

FIGURE 1 – PIN CONFIGURATION FOR WF2M32-XXX5

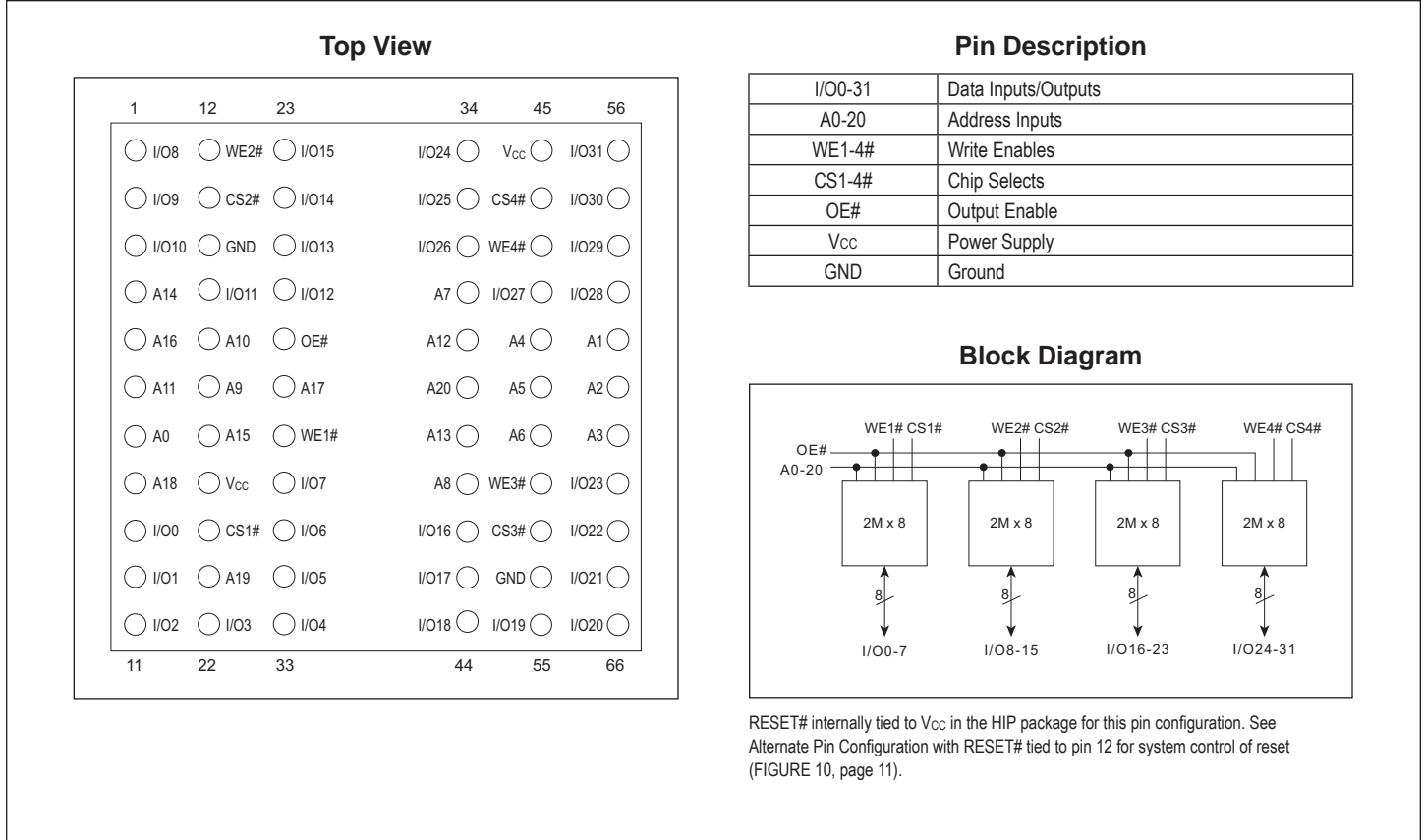
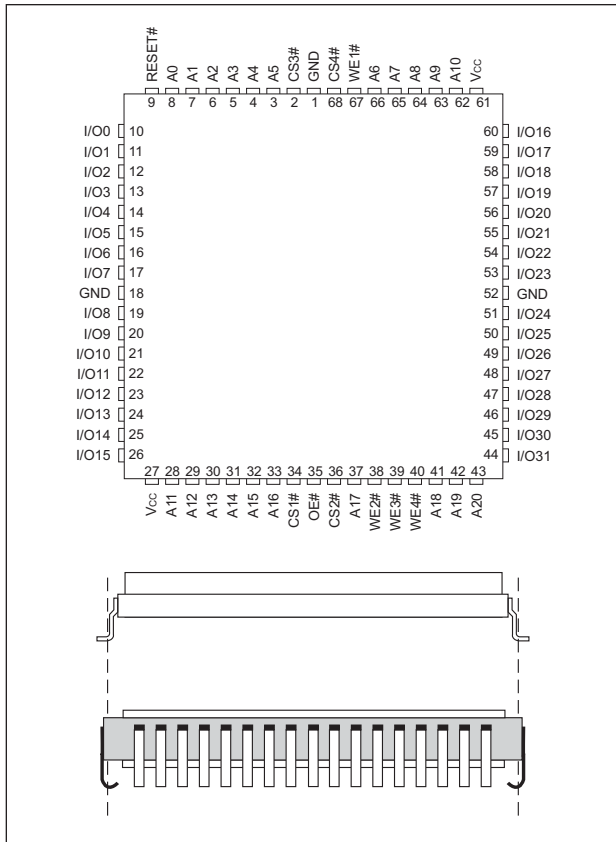


FIGURE 2 – PIN CONFIGURATION FOR WF2M32-XG2UX5

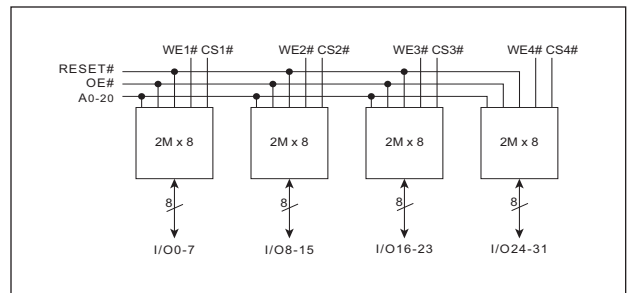
Top View



Pin Description

I/O0-31	Data Inputs/Outputs
A0-20	Address Inputs
WE1-4#	Write Enables
CS1-4#	Chip Selects
OE#	Output Enable
Vcc	Power Supply
GND	Ground
RESET#	Reset

Block Diagram



The WEDC 68 lead G2U CQFP fills the same fit and function as the JEDEC 68 lead CQJF or 68 PLCC. But the G2U has the TCE and lead inspection advantage of the CQFP form.

ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings	Unit
Voltage on Any Pin Relative to V _{SS}	V _T	-2.0 to +7.0	V
Storage Temperature	T _{stg}	-65 to +150	°C
Endurance – Write/Erase Cycles		100,000 min	cycles
Data Retention		20	years

NOTES:

- Minimum DC voltage on input or I/O pins is -0.5 V. During voltage transitions, inputs may overshoot V_{SS} to -2.0 V for periods of up to 20 ns. See . Maximum DC voltage on output and I/O pins is V_{CC} + 0.5 V. During voltage transitions, outputs may overshoot to V_{CC} + 2.0 V for periods up to 20 ns. See .
- Minimum DC input voltage on A9, OE#, RESET# pins is -0.5V. During voltage transitions, A9, OE#, RESET# pins may overshoot V_{SS} to -2.0 V for periods of up to 20 ns. See Maximum DC input voltage on A9, OE#, and RESET# is 12.5 V which may overshoot to 13.5 V for periods up to 20 ns.

Stresses greater than those listed in this section may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure of the device to absolute maximum rating conditions for extended periods may affect device reliability.

RECOMMENDED DC OPERATING CONDITIONS

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V _{CC}	4.5	5.0	5.5	V
Ground	V _{SS}	0	0	0	V
Input High Voltage	V _{IH}	2.0	-	V _{CC} + 0.5	V
Input Low Voltage	V _{IL}	-0.5	-	+0.8	V
Operating Temperature (Mil.)	T _A	-55	-	+125	°C
Operating Temperature (Ind.)	T _A	-40	-	+85	°C
Operating Temperature (Com.)	T _A	0	-	+70	°C

DC CHARACTERISTICS – CMOS COMPATIBLE

Parameter	Symbol	Conditions	Min	Max	Unit
Input Leakage Current	I _{LI}	V _{CC} = V _{CC} MAX, V _{IN} = GND to V _{CC}		10	μA
Output Leakage Current	I _{LOx32}	V _{CC} = V _{CC} MAX, V _{OUT} = GND to V _{CC}		10	μA
V _{CC} Active Current for Read (1)	I _{CC1}	CS# = V _{IL} , OE# = V _{IH} , f = 5MHz		160	mA
V _{CC} Active Current for Program or Erase (2)	I _{CC2}	CS# = V _{IL} , OE# = V _{IH}		240	mA
V _{CC} Standby Current	I _{CC3}	V _{CC} = V _{CC} MAX, CS# = V _{CC} ± 0.5V, f = 5MHz, RESET# = V _{CC} ± 0.5V		8.0	mA
Output Low Voltage	V _{OL}	I _{OL} = 12.0 mA, V _{CC} = V _{CC} MIN		0.45	V
Output High Voltage	V _{OH}	I _{OH} = -2.5 mA, V _{CC} = V _{CC} MIN	0.85xV _{CC}		V
Low V _{CC} Lock-Out Voltage	V _{LKO}		3.2	4.2	V

NOTES:

- The I_{CC} current is typically less than 8mA/MHz, with OE# at V_{IH}.
- I_{CC} active while Embedded Algorithm (program or erase) is in progress.

CAPACITANCET_A = +25°C, f = 1.0MHz

Parameter	Symbol	Max	Unit
OE# capacitance	COE	50	pF
WE1-4# capacitance HIP (PGA)	CWE	20	pF
HIP (Alternate pinout)	CWE	50	pF
CQFP G4T	CWE	50	pF
CQFP G2U	CWE	20	pF
G2U (Alternate pinout)	CWE	50	pF
CS1-4# capacitance	CCS	20	pF
Data I/O capacitance	CI/O	20	pF
Address input capacitance	CAD	50	pF

This parameter is guaranteed by design but not tested.

AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS - WE# CONTROLLED

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Write Cycle Time	t _{AVAV}	t _{WC}	90		120		150		ns
Chip Select Setup Time	t _{ELWL}	t _{CS}	0		0		0		ns
Write Enable Pulse Width	t _{WLWH}	t _{WP}	45		50		50		ns
Address Setup Time	t _{AVWL}	t _{AS}	0		0		0		ns
Data Setup Time	t _{DVWH}	t _{DS}	45		50		50		ns
Data Hold Time	t _{WHDX}	t _{DH}	0		0		0		ns
Address Hold Time	t _{WLAX}	t _{AH}	45		50		50		ns
Write Enable Pulse Width High	t _{WHWL}	t _{WPH}	20		20		20		ns
Duration of Byte Programming Operation (1)	t _{WHWH1}			300		300		300	μs
Sector Erase (2)	t _{WHWH2}			15		15		15	sec
Read Recovery Time before Write	t _{GHWL}		0		0		0		μs
V _{CC} Setup Time	t _{VCS}		50		50		50		μs
Chip Programming Time				44		44		44	sec
Chip Erase Time (3)				256		256		256	sec
Output Enable Hold Time (4)		t _{OE}	10		10		10		ns
RESET# Pulse Width (5)		t _{RP}	500		500		500		ns

NOTES:

1. Typical value for t_{WHWH1} is 7μs.
2. Typical value for t_{WHWH2} is 1sec.
3. Typical value for Chip Erase Time is 32sec.
4. For Toggle and Data Polling.
5. RESET# internally tied to V_{CC} for the default pin configuration in the HIP package.

AC CHARACTERISTICS – READ-ONLY OPERATIONS

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Read Cycle Time	t _{AVAV}	t _{RC}	90		120		150		ns
Address Access Time	t _{AVQV}	t _{ACC}		90		120		150	ns
Chip Select Access Time	t _{ELQV}	t _{CE}		90		120		150	ns
Output Enable to Output Valid	t _{GLQV}	t _{OE}		40		50		55	ns
Chip Select High to Output High Z (1)	t _{EHQZ}	t _{DF}		20		30		35	ns
Output Enable High to Output High Z (1)	t _{GHQZ}	t _{DF}		20		30		35	ns
Output Hold from Addresses, CS# or OE# Change, whichever is First	t _{AXQX}	t _{OH}	0		0		0		ns
RST Low to Read Mode (1,2)		t _{Ready}		20		20		20	μs

NOTES:

1. Guaranteed by design, not tested.
2. RESET# internally tied to V_{CC} for the default pin configuration in the HIP package.

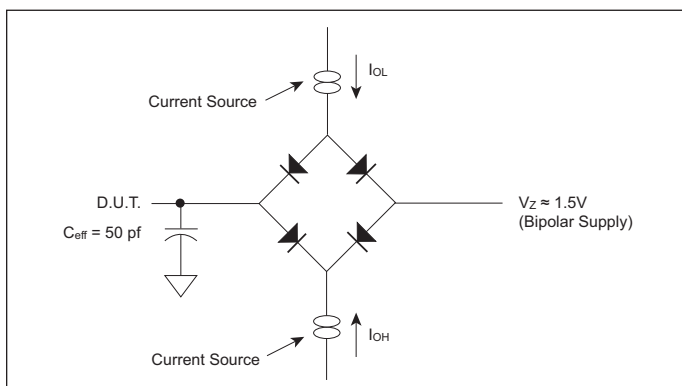
AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, CS# CONTROLLED

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Write Cycle Time	t_{AVAV}	t_{WC}	90		120		150		ns
Write Enable Setup Time	t_{WLEL}	t_{WS}	0		0		0		ns
Chip Select Pulse Width	t_{ELEH}	t_{CP}	45		50		50		ns
Address Setup Time	t_{AVEL}	t_{AS}	0		0		0		ns
Data Setup Time	t_{DVEH}	t_{DS}	45		50		50		ns
Data Hold Time	t_{EHDX}	t_{DH}	0		0		0		ns
Address Hold Time	t_{ELAX}	t_{AH}	45		50		50		ns
Chip Select Pulse Width High	t_{EHEL}	t_{CPH}	20		20		20		ns
Duration of Byte Programming Operation (1)	t_{WHWH1}			300		300		300	μ s
Sector Erase Time (2)	t_{WHWH2}			15		15		15	sec
Read Recovery Time	t_{GHEL}		0		0		0		μ s
Chip Programming Time				44		44		44	sec
Chip Erase Time (3)				256		256		256	sec
Output Enable Hold Time (4)		t_{OEHL}	10		10		10		ns

NOTES:

1. Typical value for t_{WHWH1} is 7 μ s.
2. Typical value for t_{WHWH2} is 1sec.
3. Typical value for Chip Erase Time is 32sec.
4. For Toggle and Data Polling.

FIGURE 3 – AC TEST CIRCUIT



AC TEST CONDITIONS

Parameter	Typ	Unit
Input Pulse Levels	$V_{IL} = 0, V_{IH} = 3.0$	V
Input Rise and Fall	5	ns
Input and Output Reference Level	1.5	V
Output Timing Reference Level	1.5	V

NOTES:

V_z is programmable from -2V to +7V.
 I_{OL} & I_{OH} programmable from 0 to 16mA.
 Tester Impedance $Z_0 = 75 \Omega$.
 V_z is typically the midpoint of V_{OH} and V_{OL} .
 I_{OL} & I_{OH} are adjusted to simulate a typical resistive load circuit.
 ATE tester includes jig capacitance.

FIGURE 10 – ALTERNATE PIN CONFIGURATION FOR WF2M32I-XHX5

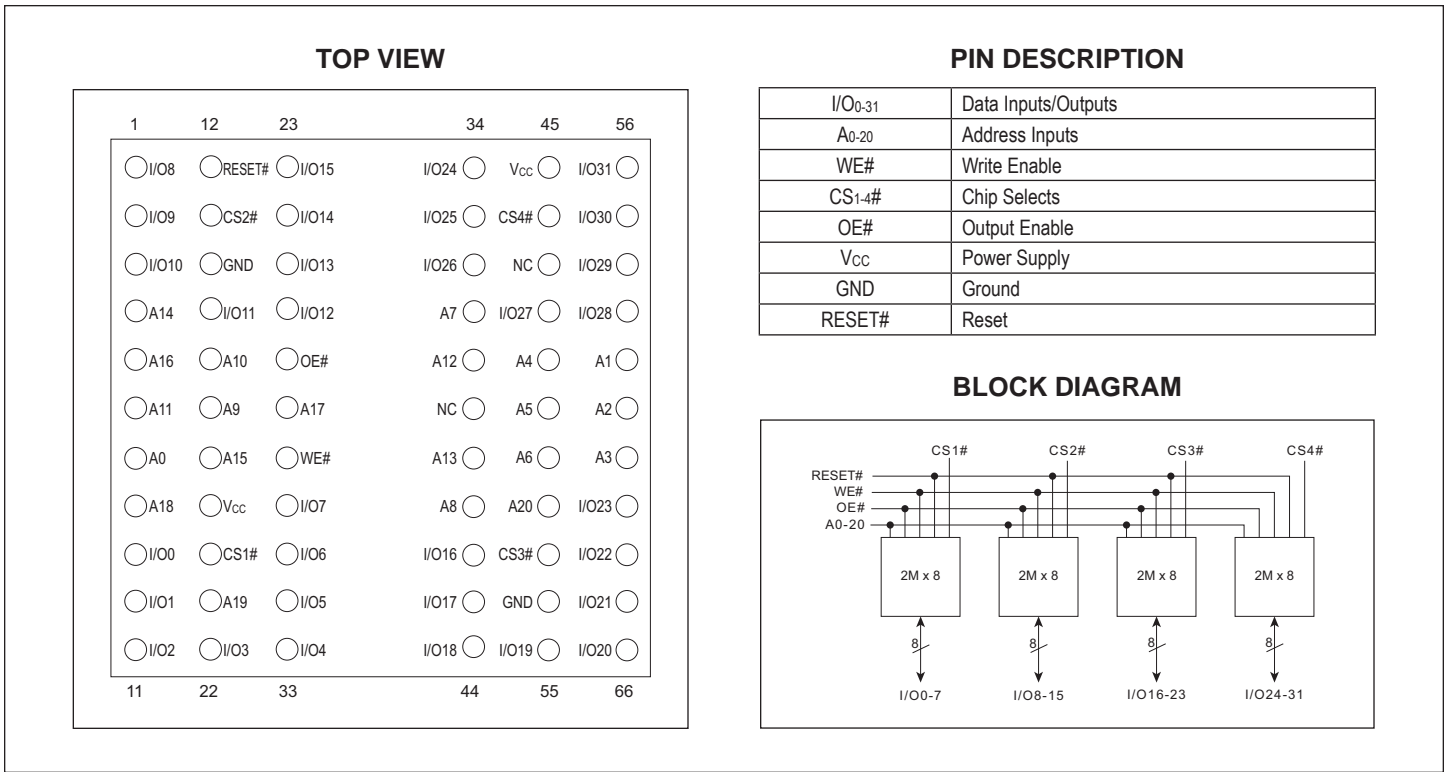


FIGURE 11 – ALTERNATE PIN CONFIGURATION FOR WF2M32U-XG2UX5

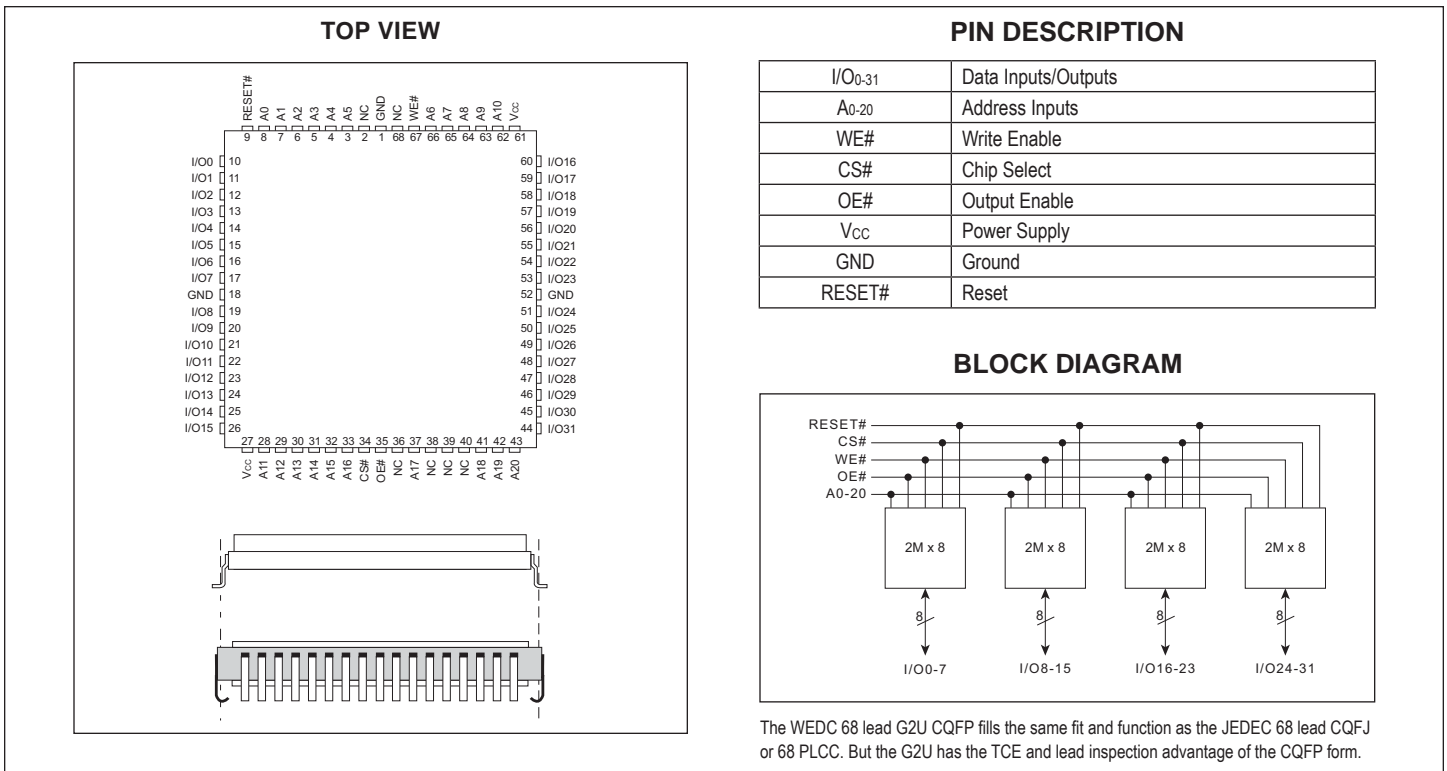
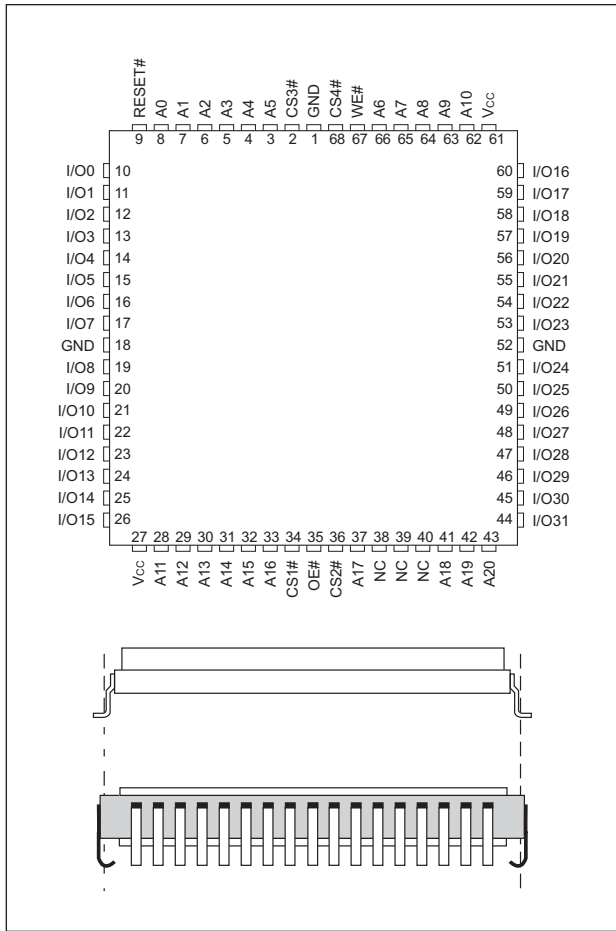


FIGURE 12 – PIN CONFIGURATION FOR WF2M32I-XG2UX5

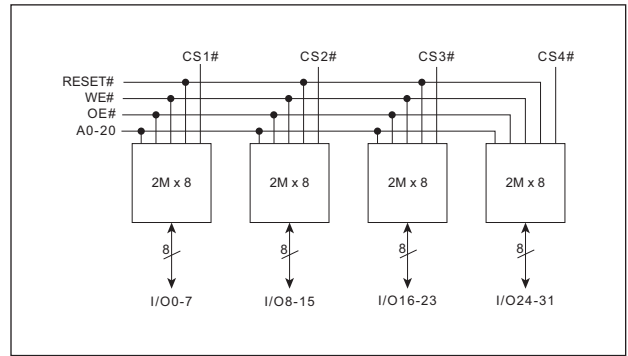
TOP VIEW



PIN DESCRIPTION

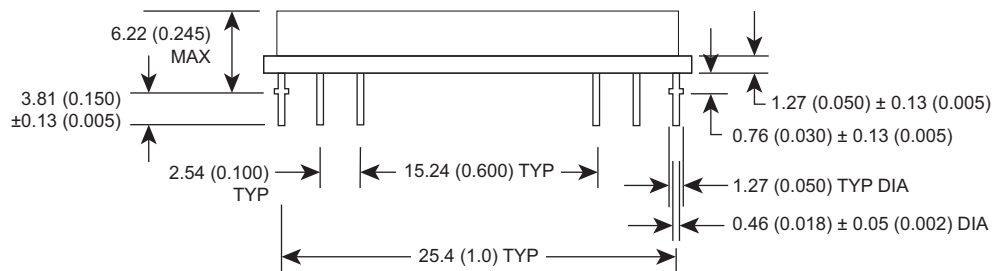
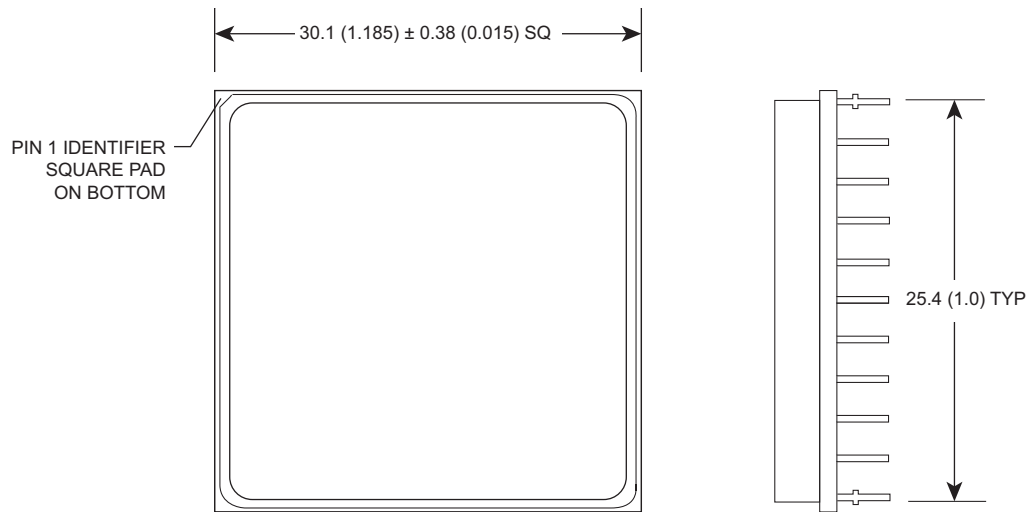
I/O0-31	Data Inputs/Outputs
A0-20	Address Inputs
WE#	Write Enable
CS1-4#	Chip Selects
OE#	Output Enable
Vcc	Power Supply
GND	Ground
RESET#	Reset

BLOCK DIAGRAM



The WEDC 68 lead G2U CQFP fills the same fit and function as the JEDEC 68 lead CQFJ or 68 PLCC. But the G2U has the TCE and lead inspection advantage of the CQFP form.

PACKAGE 401 – 66 PIN, PGA TYPE, CERAMIC HEX-IN-LINE PACKAGE, HIP (H)



ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

ORDERING INFORMATION

W F 2M32 X - XXX X X 5 X

MERCURY SYSTEMS

NOR FLASH

ORGANIZATION, 2M X 32

User configurable as 4M x 16 or 8M x 8
(Except WF2M32U-XG2UX which is 32 bit wide only.)

IMPROVEMENT MARK

• For HIP Package

Blank = 4CS# and 4WE#
I = 4CS# and 1WE#

• For G2U Package

Blank = 4CS# and 4WE#
U = 1CS# and 1WE#
I = 4CS# and 1WE#

ACCESS TIME (ns)

PACKAGE TYPE:

H = Ceramic Hex In line Package, HIP (Package 401)
G2U = 22.4mm Ceramic Quad Flat Pack, CQFP (Package 510)

DEVICE GRADE:

Q = Military Grade* ...-55°C to +125°C
M = Military.....-55°C to +125°C
I = Industrial-40°C to +85°C
C = Commercial.....0°C to +70°C

V_{PP} PROGRAMMING VOLTAGE

5 = 5 V

LEAD FINISH:

Blank = Gold plated leads
A = Solder dip leads

* This product is processed the same as the 5962-XXXXXHX product but all test and mechanical requirements are per the Mercury Systems data sheet.

Document Title

2Mx32 5V NOR FLASH MODULE

Revision History

Rev #	History	Release Date	Status
Rev 6	Change (Pg. 15) 6.1 Remove "RESET#" from ordering information	November 2009	Final
Rev 7	Change (Pg. 1-16) 7.1 Change document layout from White Electronic Designs to Microsemi	July 2011	Final
Rev 8	Change (Pg. 1, 16) 8.1 Add "NOR" to headline	August 2011	Final
Rev 9	Changes (Pg. 1, 3, 4, 5-15) 9.1 Update features 9.2 Update <i>Absolute Maximum Ratings, Recommended Operating Conditions and DC Characteristics – CMOS Compatible</i> charts 9.3 Delete subhead from all AC Characteristics charts 9.4 Delete AC Waveforms diagrams 9.5 Update package 401 – 66 Pin, PGA Type, Ceramic Hex-In-Line Package, Hip (H) diagram 9.6 Update package 510 – 68 Lead, Ceramic Quad Flat Pack, CQFP (G2U) diagram 9.7 Add NOR to Flash option and MIL - STD 883 Compliant to the "Q" device grade in the Ordering Information chart	June 2012	Final
Rev 10	Change (Pg. 10) 10 Changed Device Grade "Q" description from "MIL-STD-883 Compliant" to "MIL-PRF-38534 Class H Compliant."	May 2014	Final
Rev 11	Change (Pg. 10) 11 Changed Device Grade "Q" description from "MIL-PRF-38534 Class H Compliant" to "Military Grade."	August 2014	Final
Rev 12	Changes (Pg. All) (ECN 10156) 12.1 Change document layout from Microsemi to Mercury Systems	August 2016	Final